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Český institut pro akreditaci, o.p.s.
(Czech Accreditation Institute)
Hájkova 2747/22, Žižkov, 130 00 Praha 3

issues

according to section 16 of Act No. 22/1997 Coll., on technical requirements for products and on changes and amendments to some Acts, as amended

CERTIFICATE OF ACCREDITATION

No. 39/2026

Wabtec Inspection Technologies Czech s.r.o.
with registered office Evropská 16/176, Vokovice, 160 00 Praha 6
Company Registration No. 23193557

for the Calibration Laboratory No. 2371
NDT Calibration Laboratory

Scope of accreditation:

Calibration in the fields of length, testing of material properties and defects, and electrical quantities for Evident/Olympus flaw detectors and thickness gauges to the extent as specified in the appendix to this Certificate.

This Certificate of Accreditation is a proof of accreditation issued on the basis of assessment of fulfillment of the accreditation criteria in accordance with

ČSN EN ISO/IEC 17025:2018

In its activities performed within the scope and for the period of validity of this Certificate, the abovementioned Accredited Body is entitled to refer to this Certificate, provided that the accreditation is not suspended and the Accredited Body meets the specified accreditation requirements in accordance with the relevant regulations applicable to the activity of an accredited conformity assessment body.

This Certificate of Accreditation replaces, to the full extent, Certificate No.: 455/2025 of 11/09/2025, and/or any administrative acts building upon it.

The Certificate of Accreditation is valid until: **11/09/2030**

Prague: 26/01/2026



Signed in the Czech original:
Gor Petrosjan on 26/01/2026

Jan Velíšek
Director of the Department
of Testing and Calibration Laboratories
Czech Accreditation Institute

This translation of the Czech original has been issued by: Eliška Frycová

Accredited entity according to ČSN EN ISO/IEC 17025:2018:

Wabtec Inspection Technologies Czech s.r.o.
CAB number 2371, NDT Calibration Laboratory
Evropská 16/176, Vokovice, 160 00 Praha 6

CMC for the field of measured quantity: Length

Ord. number ¹	Calibrated quantity / Subject of calibration	Nominal range				Parameter(s) of the measurand	Lowest stated expanded measurement uncertainty ²	Calibration principle	Calibration procedure identification ³	Loca- tion
		min	unit	max	unit					
1*	Ultrasonic thickness gauges	0.150	mm	to	5.100	mm	0.005 mm 0.01 mm	Comparison with the value of a length standard	DOC-23-00018	
2*	Magnamike thickness gauges	5.100	mm	to	100.00	mm		Comparison with the value of a length standard	DOC-23-00018	
		0.250	mm	to	25.340	mm				

¹ Asterisk at the ordinal number identifies the calibrations, which the Laboratory is qualified to carry out outside the permanent laboratory premises.

² The expanded measurement uncertainty is in accordance with ILAC-P14 and EA-4/02 M a part of CMC and it is the lowest value of the respective uncertainty. If not stated otherwise, its coverage probability is approx. 95 %. If not stated otherwise, the uncertainty values stated without a unit are relative to the measured value. The uncertainty value stated herein is based on the best conditions achievable by the laboratory; the uncertainty value of a specific calibration may be higher depending on the conditions of such a calibration. For identical extreme values of adjacent ranges, the lower uncertainty value always applies.

³ If the document identifying the calibration procedure is dated only these specific procedures are used. If the document identifying the calibration procedure is not dated, the latest edition of the specified procedure is used (including any changes).

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CMC for the field of measured quantity: Testing of properties and defects of materials

Ord. number ¹	Calibrated quantity / Subject of calibration	Nominal range				Parameter(s) of the measurand	Lowest stated expanded measurement uncertainty ²	Calibration principle	Calibration procedure identification ³	Location
		min	unit	max	unit					
1*	Olympus/Evident ultrasonic thickness gauges by automatic method						1 %	Measurement with an oscilloscope (ČSN EN 15317)	DOC-23-00018	
	Pulse repetition frequency	3 Hz	to	3 kHz						
	Transmit pulse voltage	2 V	to	500 V						
	Pulse tail	2 V	to	500 V						
	Pulse rise time	2 ns	to	1,200 ns						
	Pulse duration	2 ns	to	1,200 ns						
	Current operating range	0.1 A	to	2 A						
2*	Precision and resolution	0.25 mm	to	100 mm			0.15 %	Reading from the power supply (ČSN EN 15317) Comparison with a length standard value (ČSN EN 15317)	DOC-23-00019	
	Stability after heating									
	- signal amplitude	5 % SH	to	100 % SH						
	- signal position	5 % SW	to	100 % SW						
	Display instability									
	- signal amplitude	5 % SH	to	100 % SH						
	- signal position	5 % SW	to	100 % SW						
	Stability at voltage fluctuation									
	- signal amplitude	5 % SH	to	100 % SH						
	- signal position	5 % SW	to	100 % SW						
	Transmit pulse voltage	2 V	to	500 V			3 %	Instrument display reading (ČSN EN 12668-1)		
	Pulse tail	2 V	to	500 V						
	Pulse rise time	2 ns	to	1100 ns						
	Pulse duration	2 ns	to	1100 ns						
	Amplifier frequency response	0.1 MHz	to	26.5 MHz						

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Ord. number 1	Calibrated quantity / Subject of calibration	Nominal range				Parameter(s) of the measurand	Lowest stated expanded measurement uncertainty ²	Calibration principle	Calibration procedure identification ³	Loca- tion		
		min	unit	max	unit							
	Equivalent input noise level	1 nV/ $\sqrt{\text{Hz}}$	to	80 nV/ $\sqrt{\text{Hz}}$			7 %	Calculation from measured values (ČSN EN 12668-1) Comparison with a reference attenuator (ČSN EN 12668-1) Simulation by el. signal (ČSN EN 12668-1)				
	Calibrated attenuator accuracy	0 dB	to	110 dB			0.7 dB					
	Display unit vertical linearity	5 % SH	to	100 % SH			1 % SH					
	Time base linearity	5 % SW	to	100 % SW			0.0004 % SW					
	Time resolution	50 ns	to	150 ns			2 ns	Measurement with an oscilloscope (ČSN EN ISO 22232-1)				
	Transmit pulse voltage	2 V	to	500 V			3 %					
	Pulse rise time	2 ns	to	1100 ns			2 %					
	Pulse duration	2 ns	to	1100 ns			2 %					
	Amplifier frequency response	0.1 MHz	to	26.5 MHz			2 %					
	Equivalent input noise level	1 nV/ $\sqrt{\text{Hz}}$	to	80 nV/ $\sqrt{\text{Hz}}$			7 %					
	Calibrated attenuator accuracy	0 dB	to	110 dB			0.7 dB	Instrument display reading (ČSN EN ISO 22232-1) Comparison with a reference standard (ČSN EN ISO 22232-1) Simulation by el. signal (ČSN EN ISO 22232-1)				
	Display unit vertical linearity	5 % SH	to	100 % SH			1 % SH					
	Time base linearity	5 % SW	to	100 % SW			0.0004 % SW					
	Olympus/Evident Nortec 500 series eddy current flaw detectors							Power supply reading	DOC-23-00021			
	Instrument current demand	550 mA	to	850 mA			0.006 mA					
	Instrument switching-off	7.0 V	to	8.0 V			0.06 V	Measurement by a multimeter				
	Instrument charging current	1.0 A	to	1.7 A			0.5 mA					
	Output signal amplitude	0.4 V	to	4.2 V			0.05 mV					
	Instrument driving pulse	8.20 V _{p-p}	to	10.27 V _{p-p}			0.06 V _{p-p}					
	Instrument output frequency	0 Hz	to	100 Hz			0.1 Hz					

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		min	unit	max	unit					
	Filter test Scanner output frequency - for 1200 RPM - for 3000 RPM Instrument conductivity Additional outputs Frequency No. 1 & No. 2	0 MHz 2 Hz	to	12 MHz 8 Hz			12·10 ⁻⁶ MHz 0.057 Hz	Instrument display reading Measurement by an oscilloscope		
		0 Hz 0 Hz	to	20 Hz 50 Hz			0.02 Hz 0.05 Hz			
		30 %IACS	to	60 % IACS			0.17 % IACS	Comparison with a reference standard		
				5 V			0.06 V	Measurement by an oscilloscope		
4*	Olympus/Evident Nortec 600 series eddy current flaw detectors Excitation frequency Harmonic distortion Maximum output voltage Maximum permissible output voltage Signal processing frequency response Phase linearity Gain setting accuracy Instrument maximum noise	10·10 ⁻⁶ MHz 1.8 V _{p-p} 0.1 V _{p-p} 0.1 kHz 0 °	to	10 MHz 2.2 V _{p-p} 14.4 V _{p-p} 2 kHz 360 °			2 % 0.3 % 0.3 % 0.5 % 0.1 % 0.002° 0.07 dB	Measurement with an oscilloscope (ČSN EN ISO 15548-1) Instrument display reading (ČSN EN ISO 15548-1) Comparison with a reference attenuator (ČSN EN ISO 15548-1) Calculation from measured values (ČSN EN ISO 15548-1)	DOC-23-00021	
5*	Olympus/Evident BondMaster 600 series eddy current flaw detectors Excitation frequency Harmonic distortion	1 kHz 10·10 ⁻⁶ MHz	to	500 kHz 10 MHz			2 % 0.3 %	Measurement by an oscilloscope	DOC-23-00021	

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		min	unit	max	unit					
	Maximum output voltage of TX generator (MIA, RESONANCE) and HV generator (MIA)	0.9	V _{p-p}	to	140	V _{p-p}	0.3 %			
	Output voltage linearity	0.01 %		to	0.75 %		0.5 %			
	Signal processing frequency response	70	Hz	to	80	Hz	0.1 %			
	Phase linearity	0	°	to	360	°	0.002°			
	Gain setting accuracy	0	dB	to	100	dB	0.07 dB			
	Instrument maximum noise	1.8	µV	to	15	µV	0.5 %			
6*	Olympus/Evident Omniscan series ultrasonic flaw detectors								DOC-23-00022	
	Stability after heating (mm)									
	- signal amplitude	5	% SH	to	100	% SH	0.14 % SH			
	- signal position	5	% SW	to	100	% SW	0.12 % SW			
	Display unit instability								Instrument display signal reading (ČSN EN 12668-1)	
	- signal amplitude (mm)	5	% SH	to	100	% SH	0.14 % SH			
	- signal position (mm)	5	% SW	to	100	% SW	0.12 % SW			
	Stability at voltage variations									
	- signal amplitude (mm)	5	% SH	to	100	% SH	0.14 % SH			
	- signal position (mm)	5	% SW	to	100	% SW	0.12 % SW			
	Transmit pulse voltage	2	V	to	500	V	3 %		Measurement with an oscilloscope (ČSN EN 12668-1)	
	Pulse tail	2	V	to	500	V	3 %			
	Pulse rise time	2	ns	to	1100	ns	2 %			
	Pulse duration	2	ns	to	1100	ns	2 %			
	Amplifier frequency response	0.1	MHz	to	26.5	MHz	2 %		Instrument display reading (ČSN EN 12668-1)	
	Equivalent input noise level	1	nV/√Hz	to	80	nV/√Hz	7 %		Calculation from measured values (ČSN EN 12668-1)	

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		min	unit	max	unit					
	Calibrated attenuator accuracy	0 dB	to	110 dB			0.7 dB	Comparison with a reference attenuator (ČSN EN 12668-1)		
	Display unit vertical linearity (mm)	5 % SH	to	100 % SH			1.0 % SH	Instrument display reading (ČSN EN 12668-1)		
	Time base linearity	0 µs	to	5,125 µs			0.004 µs	Simulation by el. Signal (ČSN EN 12668-1)		
	Transmit pulse voltage (PA)	2 V	to	500 V			3 %	Measurement by an oscilloscope		
	Pulse rise time (PA)	2 ns	to	1100 ns			2 %			
	Pulse duration (PA)	2 ns	to	1100 ns			2 %			
	Emission delay (PA)	0 ns	to	5 ns			0.08 ns			
	Bandwidth (PA)	0.2 MHz	to	26.5 MHz			2 %	Instrument display reading		
	Display linearity (PA)	5 % SH	to	100 % SH			0.23 % SH			
	Instrument absolute gain (PA)	5 % SH	to	100 % SH			0.23 % SH	Measurement with an oscilloscope		
	Display linearity delay (PA)	0.01 µs	to	10.01 µs			0.001 µs	Simulation by el. signal		
	Transmit pulse voltage (UT)	2 V	to	500 V			3 %	Measurement with an oscilloscope		
	Pulse rise time (UT)	2 ns	to	1100 ns			2 %			
	Pulse duration (UT)	2 ns	to	1100 ns			2 %			
	Instrument absolute gain (UT)	5 % SH	to	100 % SH			0.23 % SH			
	Bandwidth (UT)	0.2 MHz	to	26.5 MHz			2 %	Instrument display reading		
	Display linearity delay	0.01 µs	to	10.01 µs			0.001 µs	Simulation by el. signal		
	Display linearity	5 % SH	to	100 % SH			0.23 % SH	Instrument display reading		
	Transmit pulse voltage (UT)	2 V	to	500 V			3 %	Measurement with an oscilloscope		
	Pulse rise time (UT)	2 ns	to	1100 ns			2 %			
	Pulse duration (UT)	2 ns	to	1100 ns			2 %			
	Amplifier frequency response	0.2 MHz	to	26.5 MHz			2 %	Signal generation (ČSN EN ISO 22232-1)		

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		min	unit	max	unit					
	Equivalent input noise level	1 nV/√Hz	to	80 nV/√Hz			7 %	Calculation from measured values (ČSN EN ISO 22232-1) Comparison with a reference attenuator (ČSN EN ISO 22232-1) Instrument display reading (ČSN EN ISO 22232-1) Instrument display reading (ČSN EN ISO 18563-1) Measurement with an oscilloscope (ČSN EN ISO 18563-1) Simulation by el. signal (ČSN EN ISO 18563-1) Simulation by el. signal (ČSN EN ISO 18563-1) Signal generation (ČSN EN ISO 18563-1) Instrument display reading (ČSN EN ISO 18563-1) Calculation from measured values (ČSN EN ISO 18563-1) Comparison with a reference attenuator (ČSN EN ISO 18563-1) Instrument display reading (ČSN EN ISO 18563-1) Simulation by el. signal (ČSN EN ISO 18563-1) Measurement with an oscilloscope (ČSN EN ISO 18563-1) Comparison with a reference attenuator		
	Calibrated attenuator accuracy	0 dB	to	110 dB			0.7 dB			
	Display unit vertical linearity (mm)	5 % SH	to	100 % SH			1.0 % SH			
	Channel gain deviation	5 % SH	to	100 % SH			0.2 % SH			
	Transmit pulse voltage	2 V	to	500 V			3 %			
	Pulse rise time	2 ns	to	1100 ns			2 %			
	Pulse duration	2 ns	to	1100 ns			2 %			
	Delay linearity	0 ns	to	100 ns			0.07 ns			
	Transmit channel position deviation	0 ns	to	5 ns			0.07 ns			
	Amplifier frequency response	0.2 MHz	to	29 MHz			2 %			
	Channel gain deviation	5 % SH	to	100 % SH			0.2 % SH			
	Equivalent input noise level	1 nV/√Hz	to	80 nV/√Hz			7 %			
	Calibrated attenuator accuracy	0 dB	to	110 dB			0.7 dB			
	Vertical display linearity (mm)	5 % SH	to	800 % SH			1 % SH			
	Linearity of individual transmit pulses	0 ns	to	55 ns			0.07 ns			
	Instrument absolute gain (ECA)	0 V	to	1.5 V			0.01 V			
	Gain linearity (ECA)	0.1 %	to	3.0 %			0.7 %			

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		min	unit	max	unit					
	Generator excitation frequency (ECA)	0.1	MHz	to	6.1	MHz	2.0 %	Measurement with an oscilloscope		
	Output voltage verification (ECA)									
	- voltage	1	V	to	10	V	0.7 %			
	- frequency	1	Hz	to	20	Hz	2.0 %			
	General test (ECA)									
	- voltage on a connector	0	V	to	12	V	0.08 V			
	- voltage on a BNC connector	0	V	to	12	V	0.08 V			

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Explanatory notes:

IACS..... International Annealed Copper Standard

RPM..... Revolutions per minute

SH..... Screen Height

SW..... Screen Width

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CMC for the field of measured quantity: Electrical quantities

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		min	unit	max	unit					
1	DC voltage / DC voltage sources	0 mV	to	10 mV			8 µV	Direct measurement by a multimeter	DOC-25-00057	
		10 mV	to	100 mV			17 µV			
		100 mV	to	1 V			88 µV			
		1 V	to	10 V			0.8 mV			
		10 V	to	100 V			10 mV			
		100	to	1000 V			65 mV			
2	DC resistance	0 Ω	to	10 Ω			10 mΩ	Direct measurement by a multimeter	DOC-25-00057	
		10 Ω	to	100 Ω			29 mΩ			
		100 Ω	to	1 kΩ			0.2 Ω			
		1 kΩ	to	10 kΩ			2 Ω			
		10 kΩ	to	100 kΩ			20 Ω			
		100 kΩ	to	1 MΩ			0.2 kΩ			
		1 MΩ	to	10 MΩ			8 kΩ			
		10 MΩ	to	100 MΩ			0.9 MΩ			
3	HF voltage, peak-to- peak value / Sources of peak-to-peak voltage	2 mV	to	40 V	0,1 MHz to 100 MHz		3 % + 0.1 mV	Measurement with an oscilloscope with 50 Ω external load	DOC-25-00057	
4	VF attenuation / VF attenuator	0 dB	to	50 dB	0,25 MHz to do 100 MHz		0.17 dB	Measurement by a vector analyzer	DOC-25-00057	
		50 dB	to	60 dB			0.21 dB			
		60 dB	to	70 dB			0.28 dB			
		70 dB	to	80 dB			0.37 dB			
		80 dB	to	90 dB			0.57 dB			

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"This document is an appendix to the certificate of accreditation. In case of any discrepancies between the English and Czech versions, the Czech version shall prevail, both for the certificate appendix and the certificate itself. "